Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

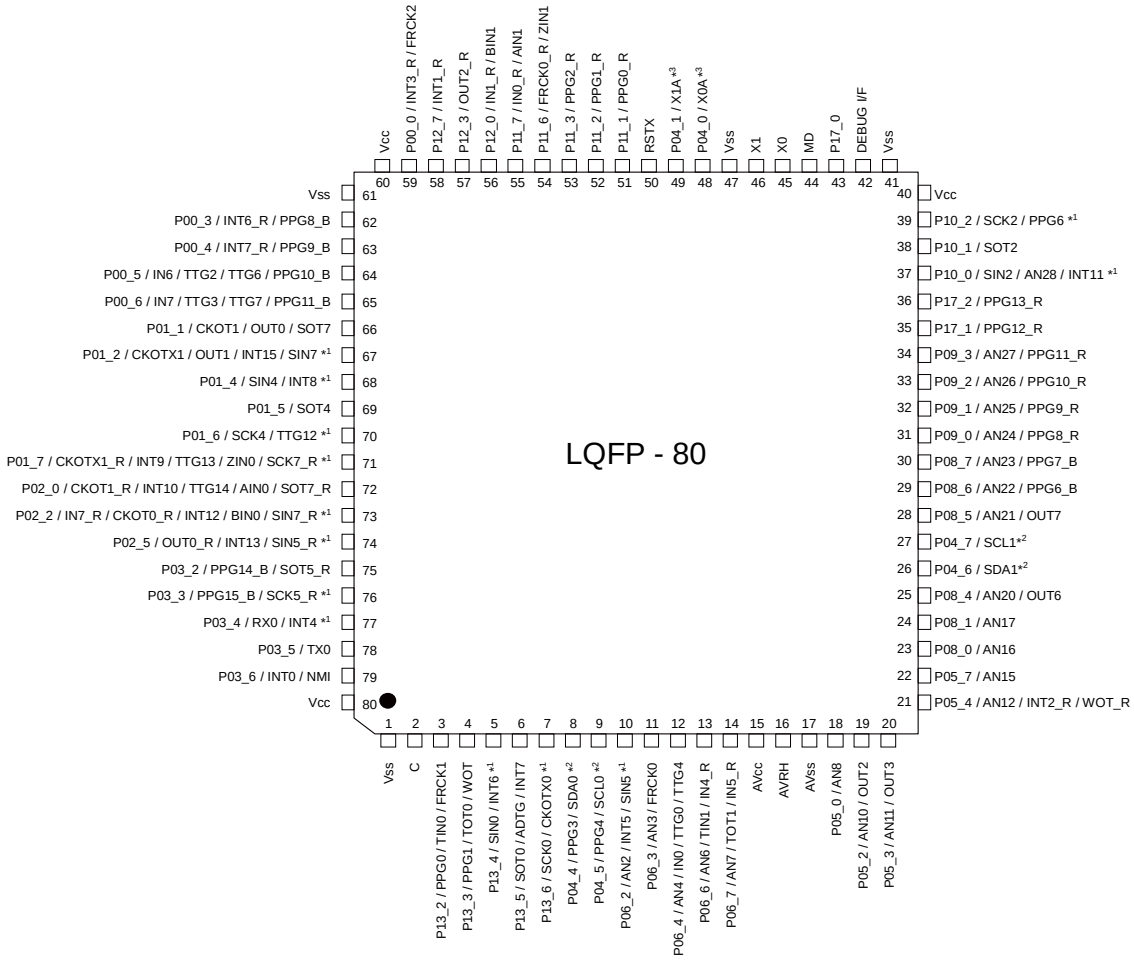
"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	F²MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I²C, LINbus, SCI, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	64
Program Memory Size	416KB (416K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	28K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 21x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	80-LQFP
Supplier Device Package	80-LQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f637rbpmc-gse2

3. Pin Assignment

(Top view)



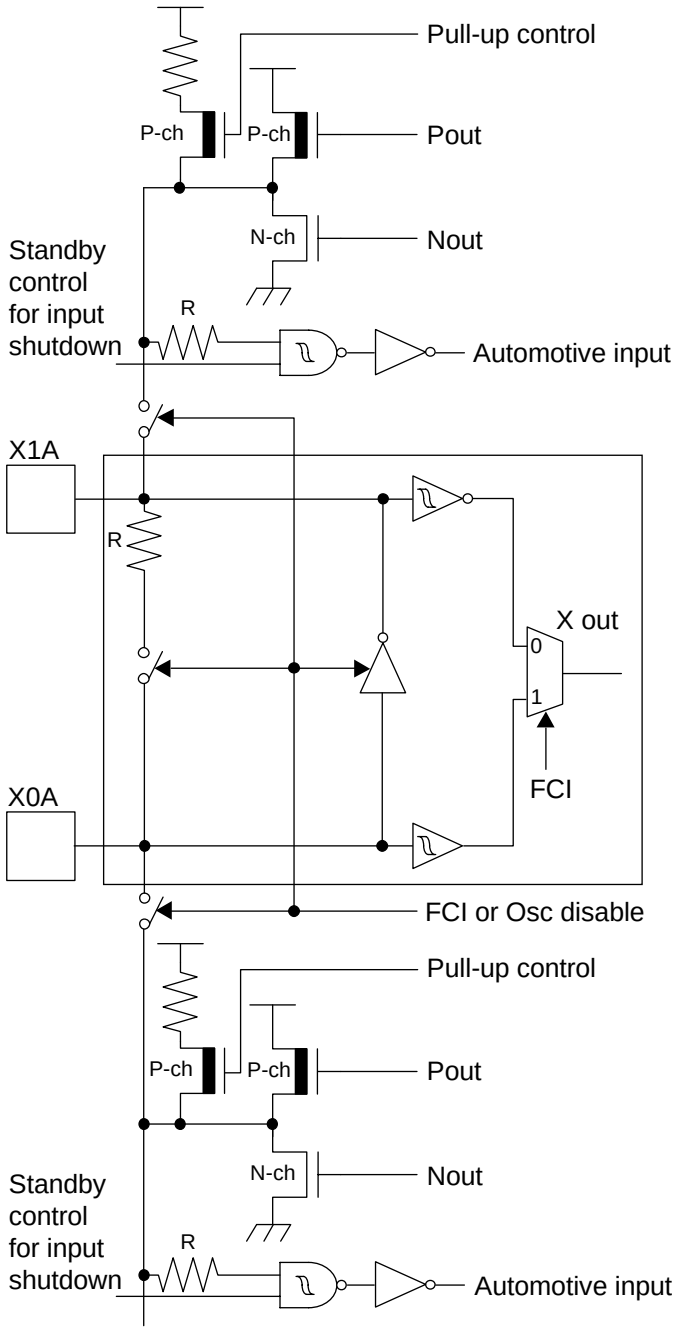
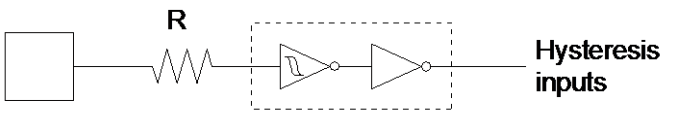
(FPT-80P-M21)

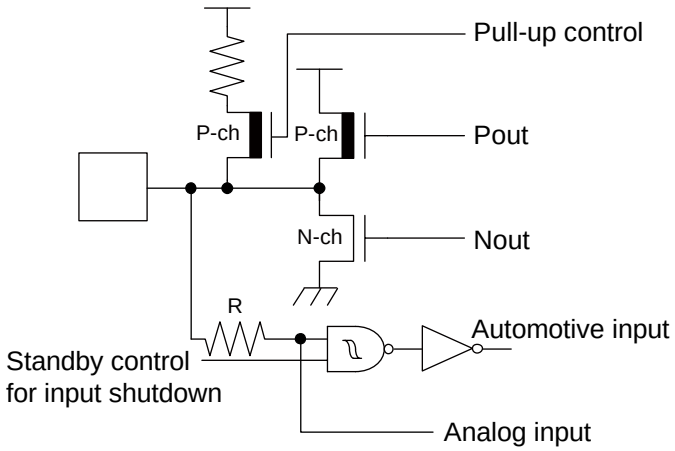
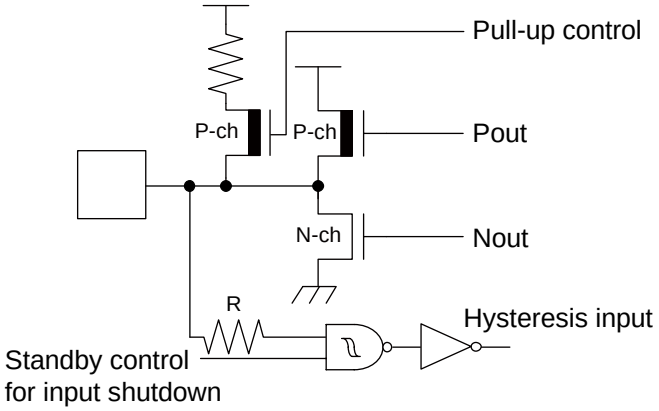
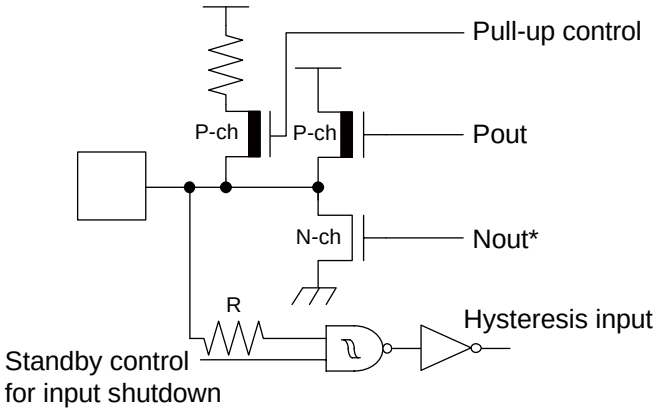
*1: CMOS input level only

*2: CMOS input level only for I^2C

*3: Please set ROM Configuration Block (RCB) to use the subclock.

Other than those above, general-purpose pins have only Automotive input level.

Type	Circuit	Remarks
B		Low-speed oscillation circuit shared with GPIO functionality: • Feedback resistor = approx. 5.0MΩ • GPIO functionality selectable (CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA), Automotive input with input shutdown function and programmable pull-up resistor)
C		CMOS hysteresis input pin

Type	Circuit	Remarks
K		• CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) • Automotive input with input shutdown function • Programmable pull-up resistor • Analog input
M		• CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) • CMOS hysteresis input with input shutdown function • Programmable pull-up resistor
N		• CMOS level output (I_{OL} = 3mA, I_{OH} = -3mA) • CMOS hysteresis input with input shutdown function • Programmable pull-up resistor *: N-channel transistor has slew rate control according to I^2C spec, irrespective of usage.

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

   Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.
2. Protection of Output Pins

   Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.
   Therefore, avoid this type of connection.
3. Handling of Unused Input Pins

   Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
2. Be sure that abnormal current flows do not occur during the power-on sequence.

■Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

13.6 Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

13.7 Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AV_{CC}, AVRH) and analog inputs (ANn) on after turning the digital power supply (V_{CC}) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, AVRH must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).

13.8 Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as $AV_{CC} = V_{CC}$, $AV_{SS} = AVRH = V_{SS}$.

13.9 Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than 50µs from 0.2V to 2.7V.

13.10 Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the V_{CC} power supply voltage, a malfunction may occur. The V_{CC} power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that V_{CC} ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard V_{CC} power supply voltage and the transient fluctuation rate becomes 0.1V/µs or less in instantaneous fluctuation for power supply switching.

13.11 Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication.

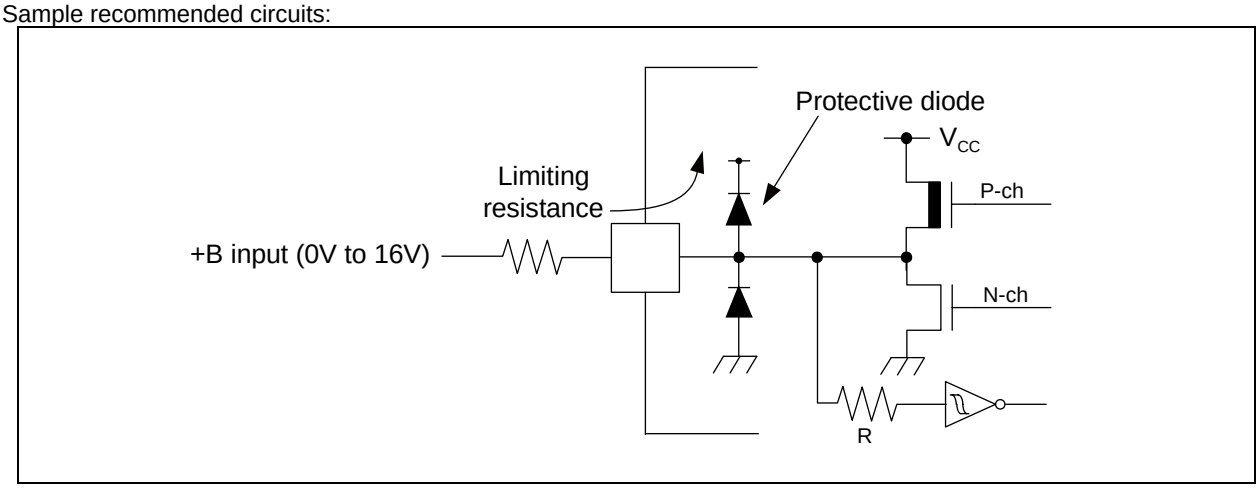
Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

13.12 Mode Pin (MD)

Connect the mode pin directly to Vcc or Vss pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to Vcc or Vss pin and provide a low-impedance connection.

- The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.
- Sample recommended circuits:



*5: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.
The actual power dissipation depends on the customer application and can be calculated as follows:
$P_D = P_{IO} + P_{INT}$
$P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports)
$P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)
I_{CC} is the total core current consumption into V_{CC} as described in the “DC characteristics” and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming.
I_A is the analog current consumption into AV_{CC}.

*6: Worst case value for a package mounted on single layer PCB at specified T_A without air flow.

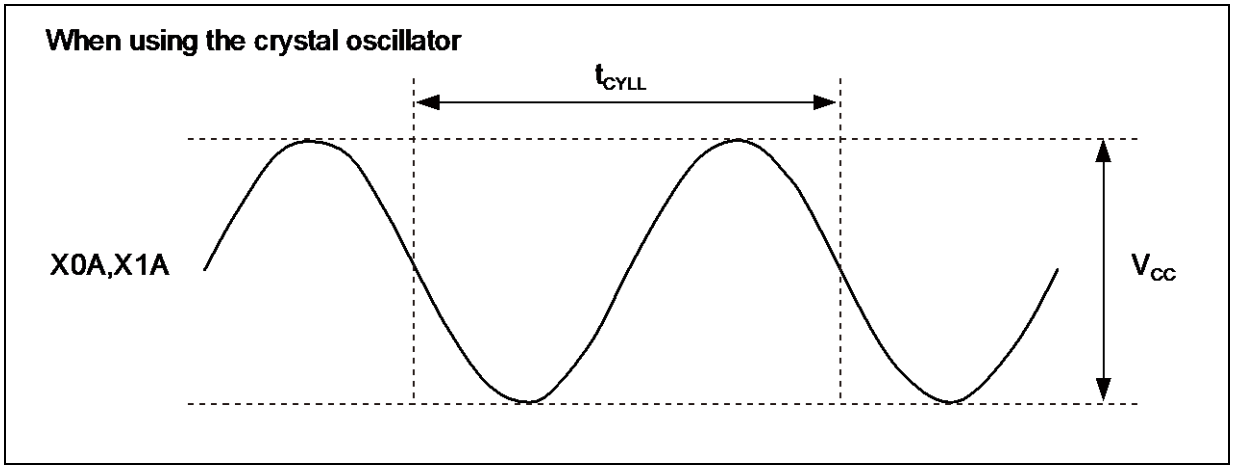
*7: Write/erase to a large sector in flash memory is warranted with TA ≤ + 105°C.

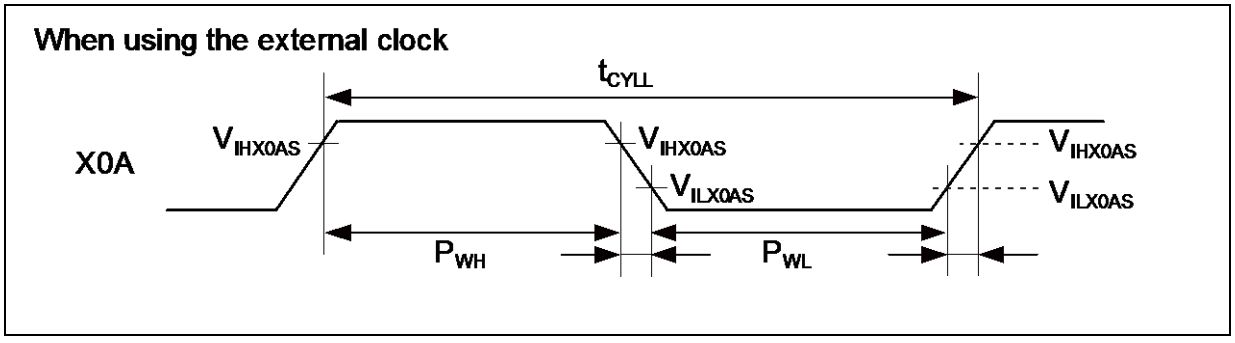
WARNING
Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

14.4.2 Sub Clock Input Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Input frequency	f_{CL}	X0A, X1A	-	-	32.768	-	kHz	When using an oscillation circuit
			-	-	-	100	kHz	When using an opposite phase external clock
		X0A	-	-	-	50	kHz	When using a single phase external clock
Input clock cycle	t_{CYLL}	-	-	10	-	-	µs	
Input clock pulse width	-	-	P_{WH}/t_{CYLL}, P_{WL}/t_{CYLL}	30	-	70	%	





14.4.3 Built-in RC Oscillation Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Value			Unit	Remarks
		Min	Typ	Max		
Clock frequency	f_{RC}	50	100	200	kHz	When using slow frequency of RC oscillator
		1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization time	t_{RCSTAB}	80	160	320	µs	When using slow frequency of RC oscillator (16 RC clock cycles)
		64	128	256	µs	When using fast frequency of RC oscillator (256 RC clock cycles)

14.4.4 Internal Clock Timing

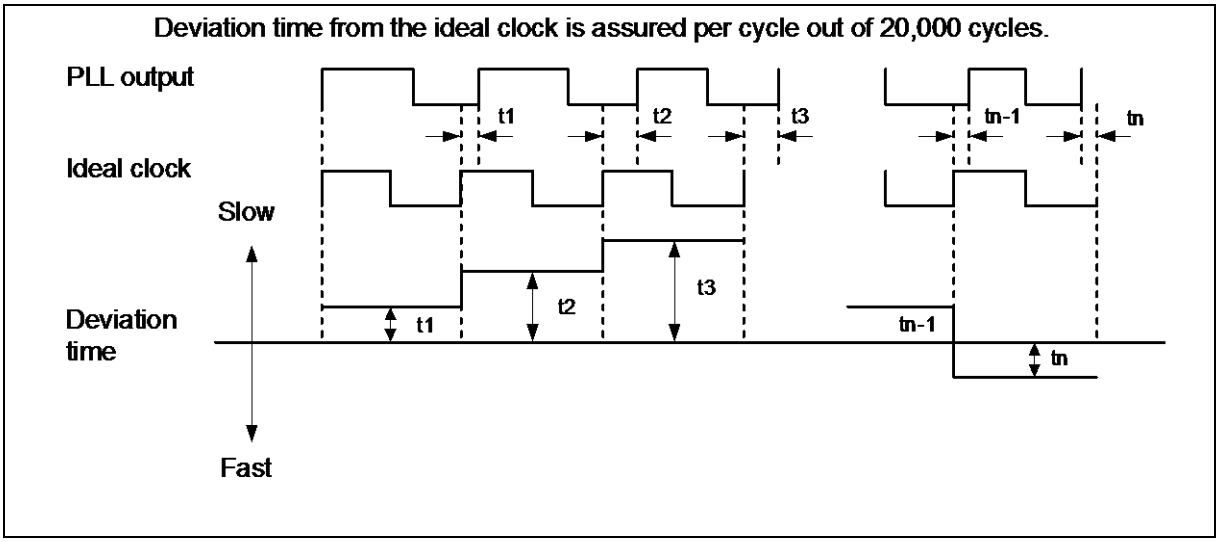
(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Value		Unit
		Min	Max	
Internal System clock frequency (CLKS1 and CLKS2)	f_{CLKS1}, f_{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f_{CLKB}, f_{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f_{CLKP2}	-	32	MHz

14.4.5 Operating Conditions of PLL

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

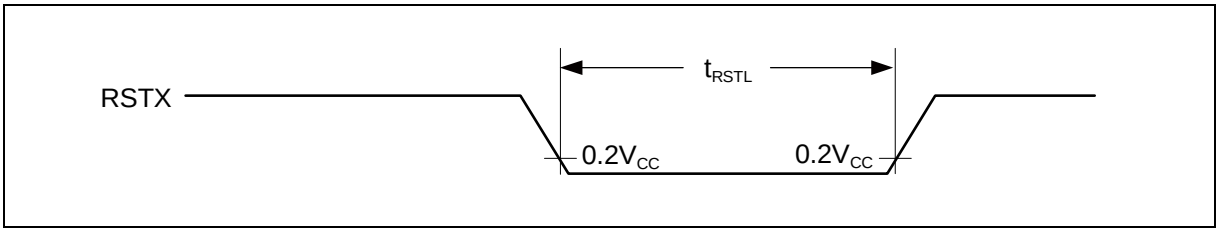
Parameter	Symbol	Value			Unit	Remarks
		Min	Typ	Max		
PLL oscillation stabilization wait time	t_{LOCK}	1	-	4	ms	For CLKMC = 4MHz
PLL input clock frequency	f_{PLLI}	4	-	8	MHz	
PLL oscillation clock frequency	f_{CLKVCO}	56	-	108	MHz	Permitted VCO output frequency of PLL (CLKVCO)
PLL phase jitter	t_{PSKEW}	-5	-	+5	ns	For CLKMC (PLL input clock) ≥ 4MHz

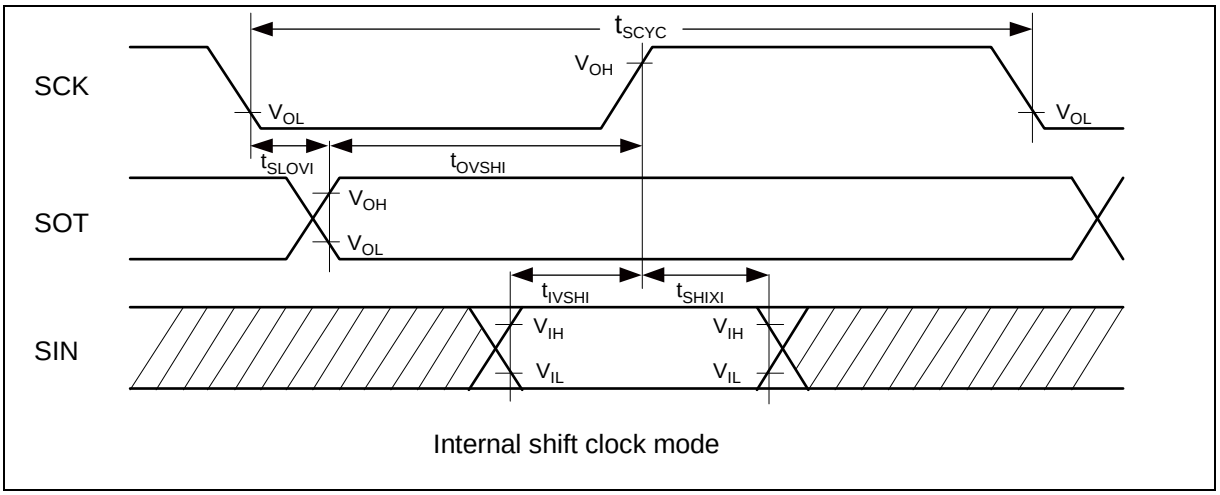


14.4.6 Reset Input

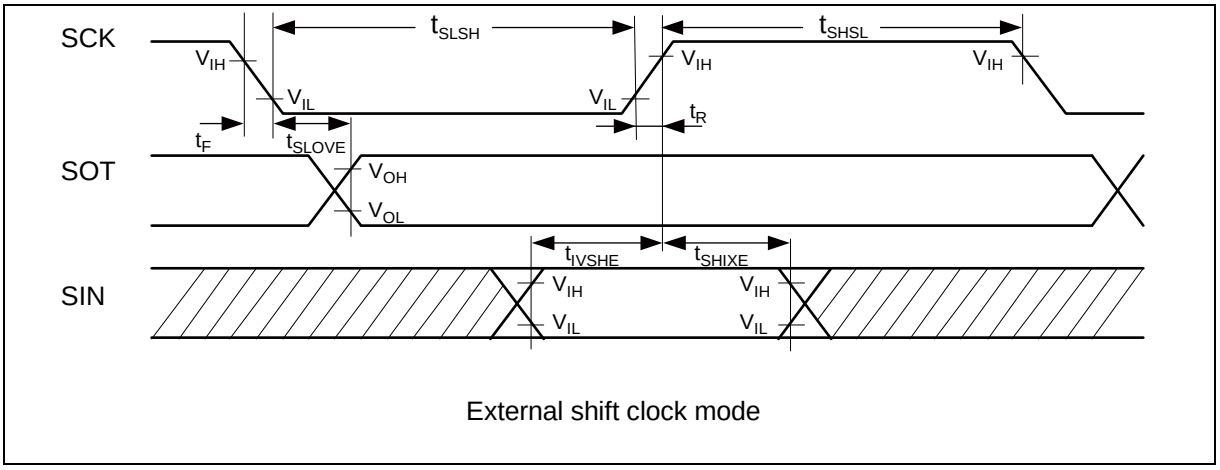
(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Value		Unit
			Min	Max	
Reset input time	t_{RSTL}	RSTX	10	-	µs
Rejection of reset input time			1	-	µs





Internal shift clock mode



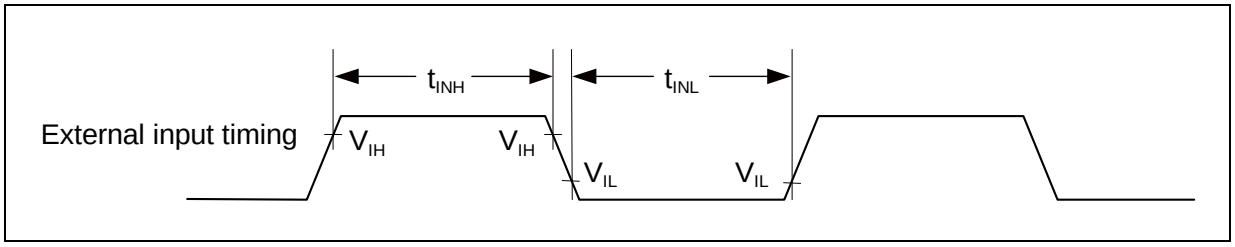
External shift clock mode

14.4.9 External Input Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Value		Unit	Remarks
			Min	Max		
Input pulse width	t_{INH}, t_{INL}	Pnn_m	$2t_{CLKP1}$ +200 (t_{CLKP1}= $1/f_{CLKP1}$)*	-	ns	General Purpose I/O
		ADTG				A/D Converter trigger input
		TINn				Reload Timer
		TTGn				PPG trigger input
		FRCKn, FRCKn_R				Free-Running Timer input clock
		INn, INn_R				Input Capture
		AINn, BINn, ZINn				Quadrature Position/Revolution Counter
		INTn, INTn_R	200	-	ns	External Interrupt
		NMI				Non-Maskable Interrupt

*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



14.4.10 I^2C Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Conditions	Typical mode		High-speed mode*4		Unit
			Min	Max	Min	Max	
SCL clock frequency	f_{SCL}	C_L = 50pF, R = (Vp/I_{OL})*1	0	100	0	400	kHz
(Repeated) START condition hold time SDA ↓ → SCL ↓	t_{HDSTA}		4.0	-	0.6	-	µs
SCL clock "L" width	t_{LOW}		4.7	-	1.3	-	µs
SCL clock "H" width	t_{HIGH}		4.0	-	0.6	-	µs
(Repeated) START condition setup time SCL ↑ → SDA ↓	t_{SUSTA}		4.7	-	0.6	-	µs
Data hold time SCL ↓ → SDA ↓ ↑	t_{HDDAT}		0	3.45*2	0	0.9*3	µs
Data setup time SDA ↓ ↑ → SCL ↑	t_{SUDAT}		250	-	100	-	ns
STOP condition setup time SCL ↑ → SDA ↑	t_{SUSTO}		4.0	-	0.6	-	µs
Bus free time between "STOP condition" and "START condition"	t_{BUS}		4.7	-	1.3	-	µs
Pulse width of spikes which will be suppressed by input noise filter	t_{SP}	-	0	(1-1.5) × t_{CLKP1}*5	0	(1-1.5) × t_{CLKP1}*5	ns

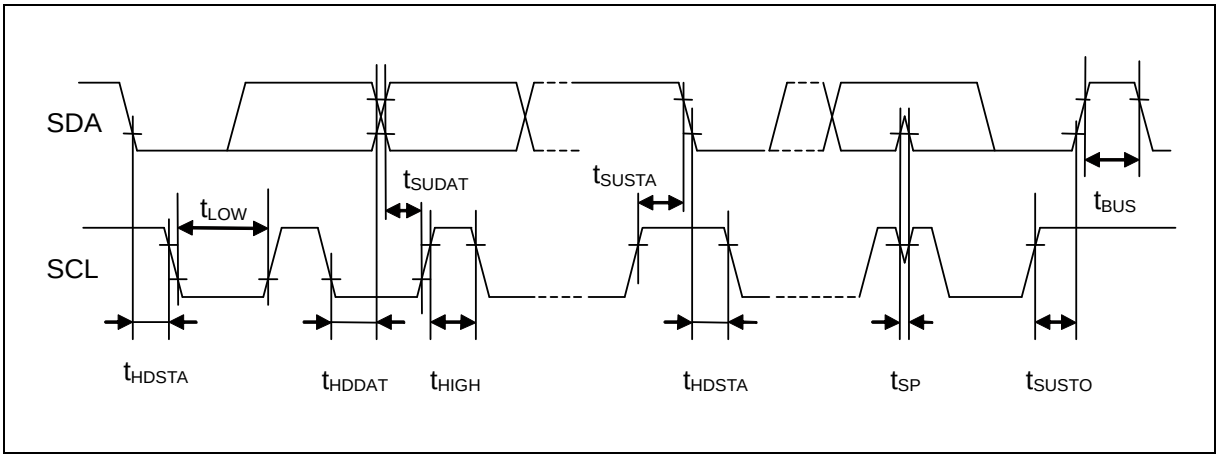
*1: R and C_L represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and I_{OL} indicates V_{OL} guaranteed current.

*2: The maximum t_{HDDAT} only has to be met if the device does not extend the "L" width (t_{LOW}) of the SCL signal.

*3: A high-speed mode I^2C bus device can be used on a standard mode I^2C bus system as long as the device satisfies the requirement of "t_{SUDAT} ≥ 250ns".

*4: For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.

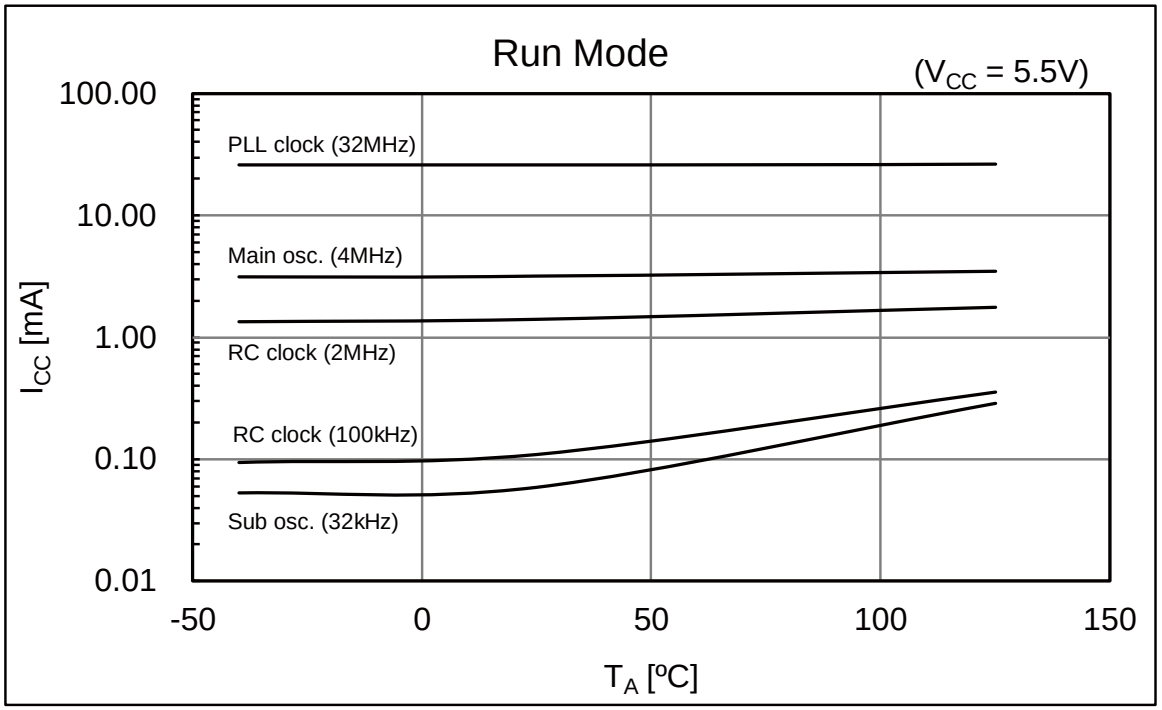
*5: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time.

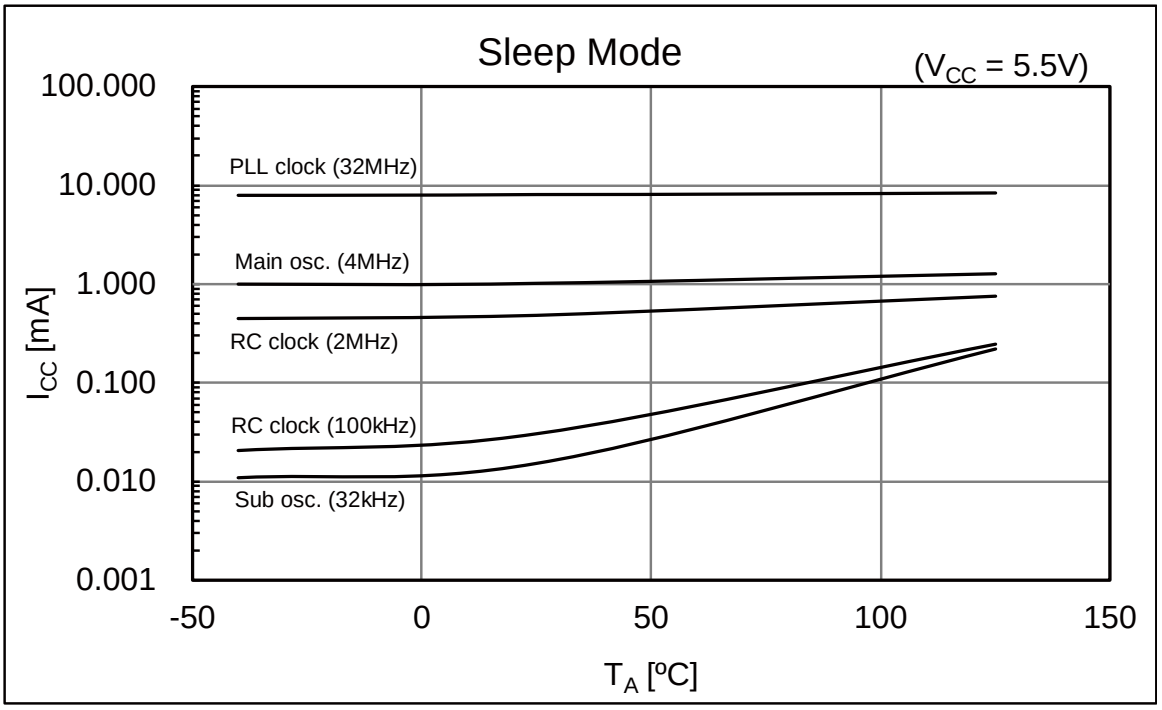


15. Example Characteristics

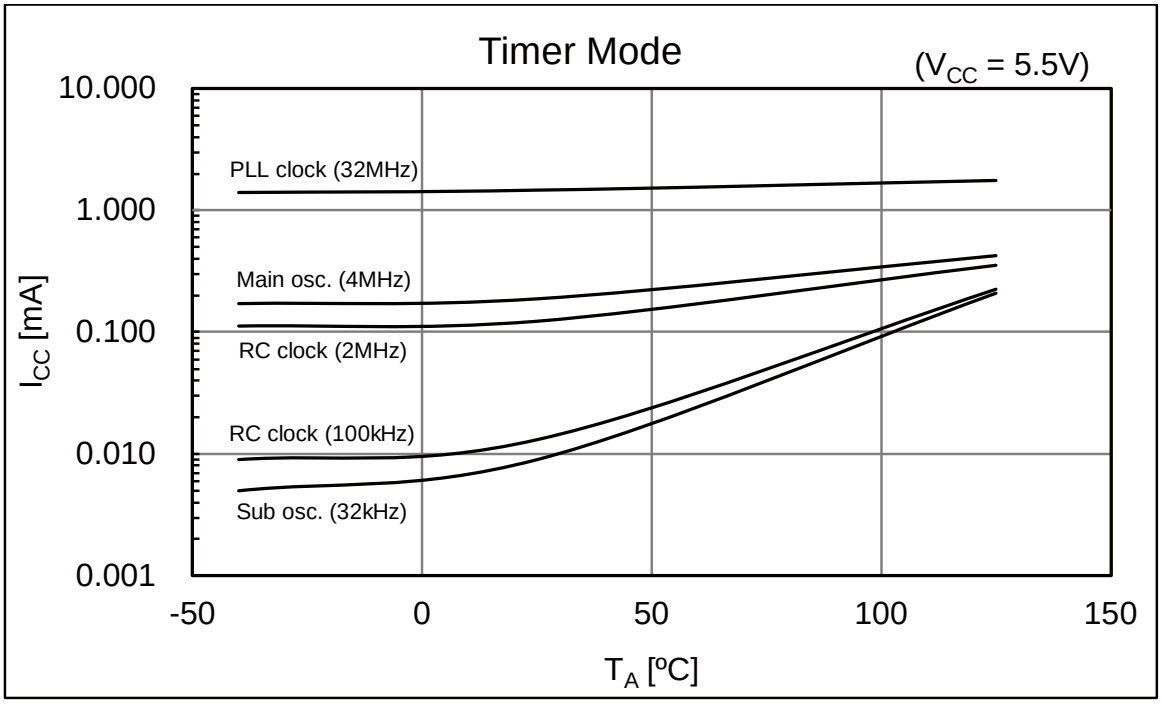
This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value.

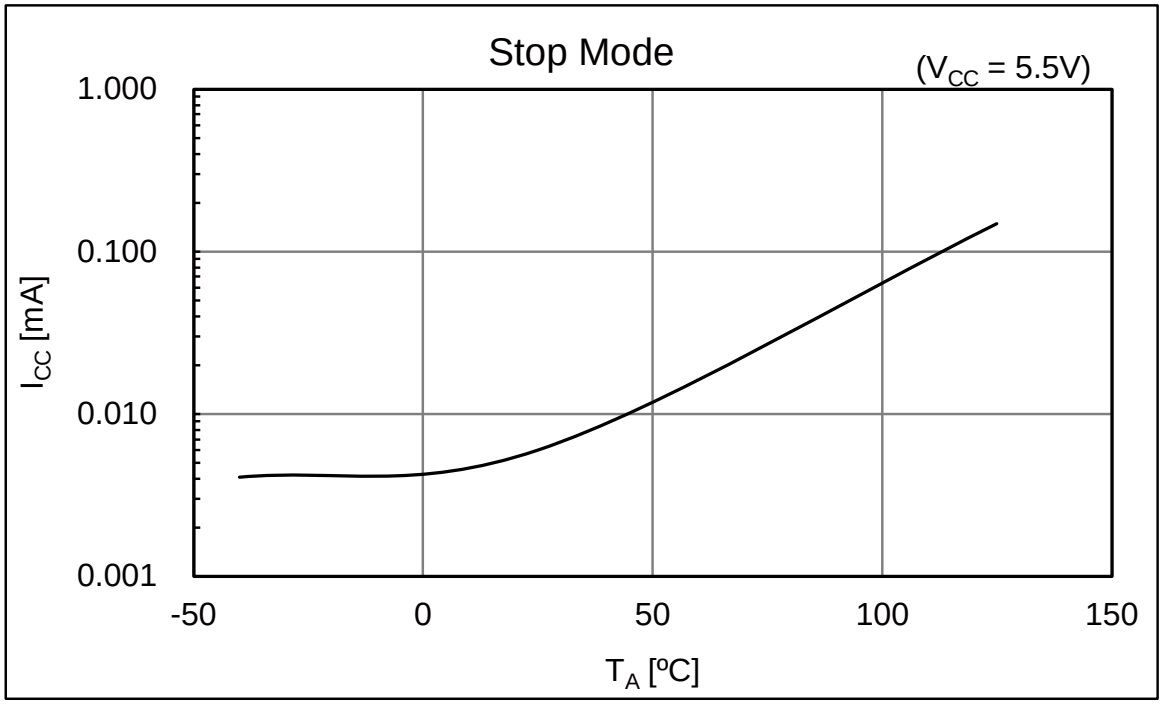
■MB96F637





■MB96F637


Timer Mode
(V_{CC} = 5.5V)
10.000
1.000
0.100
0.010
0.001
I_{CC} [mA]
PLL clock (32MHz)
Main osc. (4MHz)
RC clock (2MHz)
RC clock (100kHz)
Sub osc. (32kHz)
-50
0
50
100
150
T_A [ºC]


Stop Mode
(V_{CC} = 5.5V)
1.000
0.100
0.010
0.001
I_{CC} [mA]
-50
0
50
100
150
T_A [ºC]

■Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 4MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 2MHz Regulator in High Power Mode, (CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 100kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32kHz Regulator in Low Power Mode, (CLKB is stopped in this mode)
Timer mode	PLL	CLKMC = 4MHz, CLKPLL = 32MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz (System clocks are stopped in this mode) Regulator in High Power Mode, FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz (System clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode) Regulator in Low Power Mode, FLASH in Power-down / reset mode

16. Ordering Information

MCU with CAN controller

Part number	Flash memory	Package*
MB96F633RBPMC-GSE1	Flash A (96.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F633RBPMC-GSE2		
MB96F635RBPMC-GSE1	Flash A (160.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F635RBPMC-GSE2		
MB96F636RBPMC-GSE1	Flash A (288.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F636RBPMC-GSE2		
MB96F637RBPMC-GSE1	Flash A (416.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F637RBPMC-GSE2		

*: For details about package, see "Package Dimension".

MCU without CAN controller

Part number	Flash memory	Package*
MB96F633ABPMC-GSE1	Flash A (96.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F633ABPMC-GSE2		
MB96F635ABPMC-GSE1	Flash A (160.5KB)	80-pin plastic LQFP (FPT-80P-M21)
MB96F635ABPMC-GSE2		

*: For details about package, see "Package Dimension".

18. Major Changes

Spansion Publication Number: MB96F636-DS704-00012

Page	Section	Change Results
Revision 1.0		
-	-	PRELIMINARY → Data sheet
2	Features	Changed the description of “System clock” Up to 16 MHz external clock for devices with fast clock input feature → Up to 8 MHz external clock for devices with fast clock input feature
4		Changed the description of “External Interrupts” Interrupt mask and pending bit per channel → Interrupt mask bit per channel
		Changed the description of “Built-in On Chip Debugger” - Event sequencer: 2 levels → - Event sequencer: 2 levels + reset
5	Product Lineup	Added the Product
		Changed the Remark of RLT RLT 0/1/6 Only RLT6 can be used as PPG clock source → RLT 0/1/6
6	Block Diagram	Deleted the block of RLT6 from PPG block
		Changed the RLT block 2ch → 0/1/6 3ch
8	Pin Description	Changed the Description of PPGn_B Programmable Pulse Generator n output (8bit) → Programmable Pulse Generator n output (16bit/8bit)
13	I/O Circuit Type	Changed the figure of type B
		Changed the Remarks of type B (CMOS hysteresis input with input shutdown function, I_{OL} = 4mA, I_{OH} = -4mA, Programmable pull-up resister) → (CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA), Automotive input with input shutdown function and programmable pull-up resistor)
14		Changed the figure of type G
17	Memory Map	Changed the START addresses of Boot-ROM $0F:E000_H$ → $0F:C000_H$
19	User Rom Memory Map For Flash Devices	Changed the annotation Others (from $DF:0200_H$ to $DF:1FFF_H$) are all mirror area of SAS-512B. → Others (from $DF:0200_H$ to $DF:1FFF_H$) is mirror area of SAS-512B.

Page	Section	Change Results
39	3. DC Characteristics (1) Current Rating	Changed the Value of “Power supply current in Stop modes” I_{CCH} Max: 90µA → 60µA (T_A = +25°C) Max: 985µA → 880µA (T_A = +105°C) Max: 1985µA → 1845µA (T_A = +125°C)
		Added the Symbol $I_{CCFLASHPD}$
		Changed the Value and condition of “Power supply current for active Low Voltage detector” I_{CCLVD} Typ: 5µA, Max: 15µA, Remarks: nothing → Typ: 5µA, Max: -, Remarks: T_A = +25°C Typ: -, Max: 12.5µA, Remarks: T_A = +125°C
		Changed the condition of “Flash Write/Erase current” $I_{CCFLASH}$ Typ: 12.5mA, Max: 20mA, Remarks: nothing → Typ: 12.5mA, Max: -, Remarks: T_A = +25°C Typ: -, Max: 20mA, Remarks: T_A = +125°C
		Changed the annotation *2 The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. → When Flash is not in Power-down / reset mode, $I_{CCFLASHPD}$ must be added to the Power supply current. The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.
40	3. DC Characteristics (2) Pin Characteristics	Added the Symbol for DEBUG I/F pin V_{OLD}
41		Changed the Pin name of “Input capacitance” Other than Vcc, Vss, AVcc, AVss, AVRH → Other than C, Vcc, Vss, AVcc, AVss, AVRH
		Deleted the annotation “I_{OH} and I_{OL} are target value.”
42	4. AC Characteristics (1) Main Clock Input Characteristics	Changed MAX frequency for f_{FCI} in all conditions 16→8 Changed MIN frequency for t_{CYLH} 62.5→125 Changed MIN, MAX and Unit for P_{WH} , P_{WL} MIN: 30→55 MAX: 70→- Unit: %→ns
		Added the figure (t_{CYLH}) when using the external clock
43	4. AC Characteristics (2) Sub Clock Input Characteristics	Added the figure (t_{CYLL}) when using the crystal oscillator clock

Page	Section	Change Results
44	4. AC Characteristics (3) Built-In RC Oscillation Characteristics	Added “RC clock stabilization time”
45	4. AC Characteristics (5) Operating Conditions Of PLL	Changed the Value of “PLL input clock frequency” Max: 16MHz → 8MHz
		Changed the Symbol of “PLL oscillation clock frequency” f_{PLLO} → f_{CLKVCO}
		Added Remarks to “PLL oscillation clock frequency”
		Added “ PLL phase jitter” and the figure
	4. Ac Characteristics (6) Reset Input	Added the figure for reset input time (t_{RSTL})
47	4. Ac Characteristics (8) Usart Timing	Changed the condition (VCC = AVCC = 2.7V to 5.5V, VSS = AVSS = 0V, TA = - 40°C to + 105°C) → (V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C, C_L=50pF)
		Changed the HARDWARE MANUAL “MB96630 series HARDWARE MANUAL” → “MB96600 series HARDWARE MANUAL”
48		Changed the figure for “Internal shift clock mode”
50	4. AC Characteristics (10) I^2C Timing	Added parameter, “Noise filter” and an annotation *5 for it
		Added t_{SP} to the figure
51	5. A/D Converter (1) Electrical Characteristics For The A/D Converter	Added “Analog impedance”
		Added “Variation between channels”
		Added the annotation
52	5. A/D Converter (2) Accuracy And Setting Of The A/D Converter Sampling Time	Deleted the unit “[Min]” from approximation formula of Sampling time
53	5. A/D Converter (3) Definition Of A/D Converter Terms	Changed the Description and the figure “Linearity” → “Nonlinearity” “Differential linearity error” → “Differential nonlinearity error”
		Changed the Description Linearity error: Deviation of the line between the zero-transition point (0b0000000000←→0b0000000001) and the full-scale transition point (0b1111111110←→0b1111111111) from the actual conversion characteristics. → Nonlinearity error: Deviation of the actual conversion characteristics from a straight line that connects the zero transition point (0b0000000000 ←→ 0b0000000001) to the full-scale transition point (0b1111111110 ←→ 0b1111111111).
		Added the Description “Zero transition voltage” “Full scale transition voltage”
55	6. Low Voltage Detection Function Characteristics	Added the Value of “ Power supply voltage change rate” Max: +0.004 V/µs
		Added “Hysteresis width” (V_{HYS})
		Added “Stabilization time” ($T_{LVDSTAB}$)
		Added “Detection delay time” (t_d)
		Deleted the Remarks
		Added the annotation *1, *2
56		Added the figure for “Hysteresis width”
		Added the figure for “Stabilization time”

Page	Section	Change Results
57	7. Flash Memory Write/Erase Characteristics	Changed the Value of “Sector erase time”
		Added “Security Sector” to “Sector erase time”
		Changed the Parameter “Half word (16 bit) write time” → “Word (16-bit) write time”
		Changed the Value of “Chip erase time”
		Changed the Remarks of “Sector erase time” Excludes write time prior to internal erase → Includes write time prior to internal erase
		Added the Note and annotation *1
		Deleted “(targeted value)” from title “ Write/Erase cycles and data hold time”
58 to 60	Example Characteristics	Added a section
61	Ordering Information	Changed part number MCU with CAN controller MB96F636RAPMC-GSE1* → MB96F636RBPMC-GSE1 MB96F636RAPMC-GSE2* → MB96F636RBPMC-GSE2 MB96F637RAPMC-GSE1* → MB96F637RBPMC-GSE1 MB96F637RAPMC-GSE2* → MB96F637RBPMC-GSE2
61	Ordering Information	Added part number MCU with CAN controller MB96F633RBPMC-GSE1 MB96F633RBPMC-GSE2 MB96F635RBPMC-GSE1 MB96F635RBPMC-GSE2 MCU without CAN controller MB96F633ABPMC-GSE1 MB96F633ABPMC-GSE2 MB96F635ABPMC-GSE1 MB96F635ABPMC-GSE2
Revision 1.1		
-	-	Company name and layout design change

NOTE: Please see “Document History” about later revised information.